

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
MI22-1850

SERIAL NO.

10 777,555

LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)

APPLICANT: John T. Moore et al.

FILING DATE
October 31, 2001GROUP
2813

U.S. PATENT DOCUMENTS

Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
CAT	AA	09/921,518		Moore (as filed and as amended)	—	—	08/01/2001
CAT	AB	10/061,825		Gilton et al. (as filed)	—	—	01/31/2002
CAT	AC	4,405,710	09/20/83	Balasubramanyam et al.	430	311	
CAT	AD	4,419,421	12/06/83	Wichelhaus et al.	429	191	
CAT	AE	4,499,557	02/12/85	Holmberg et al.	365	163	
CAT	AF	5,315,131	05/24/94	Kishimoto et al.	257	57	
CAT	AG	5,350,484	09/27/94	Gardner et al.	156	628	
CAT	AH	5,512,328	04/30/96	Yoshimura et al.	427	498	
CAT	AI	5,512,773	04/30/96	Wolf et al.	257	471	
CAT	AJ	5,846,889	12/08/98	Harbison et al.	501	40	
CAT	AK	6,117,720	09/12/00	Harshfield	438	238	

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
CAT	AL	56126916 A	05.10.81	Abstract: Japan (Akira et al.)			X	
CAT	AM	00/48196 A1	17.08.00	WIPO (Kozicki et al.)				
CAT	AN	02/21542 A1	14.03.02	WIPO (Kozicki et al.)				
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1850	SERIAL NO. 09/999,883 1,755	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT: John T. Moore et al.		
				FILING DATE October 31, 2001		GROUP 2813

U.S. PATENT DOCUMENTS							
Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
CAT	AA	6,143,604	11/07/00	Chiang et al.	438	253	—
CAT	AB	6,177,338 B1	01/23/01	Liaw et al.	438	629	—
CAT	AC	6,350,679 B1	02/26/02	McDaniel et al.	438	634	—
	AD						
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FOREIGN PATENT DOCUMENTS								
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)			
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EXAMINER <i>Craig A. Shaw</i>	DATE CONSIDERED <i>26 APR 05</i>
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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. MI22-1850		PRIORITY SERIAL NO. 09/797,635		
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					10/777 755				
					APPLICANT John T. Moore et al.		PRIORITY FILING DATE March 1, 2001		PRIORITY GROUP 2813
U.S. PATENT DOCUMENTS									
Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date (if Appropriate)		
CAT	AA	09/732,968		Gilton (as Filed)	—	—	12/08/2000		
CAT	AB	09/779,983		Moore	—	—	02/08/01		
CAT	AC	09/943,100		Campbell, et al.	—	—	08/29/01		
CAT	AD	09/943,109		Campbell, et al.	—	—	08/29/01		
CAT	AE	09/943,187		Campbell, et al.	—	—	08/29/01		
CAT	AF	5,238,882	08/24/93	Bislock et al.	437	52			
CAT	AG	5,360,981	11/01/94	Owen et al.	257	4			
CAT	AH	5,781,115	06/02/98	Kozicki et al.	365	182			
CAT	AI	5,896,312	04/20/98	Kozicki et al.	365	153			
CAT	AJ	5,914,893	06/22/99	Kozicki et al.	365	107			
CAT	AK	6,084,796	07/04/00	Kozicki et al.	365	153			
FOREIGN PATENT DOCUMENTS									
		Document Number	Date	Country	Class	Subclass	Translation		
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)									
CAT	AR		Hirose, et al., "High Speed Memory Behavior and Reliability of an Amorphous As ₂ S ₃ Film Doped with Ag", July 17, 1980, pps. K187-K190.						
CAT	AS		Hirose, et al., "Polarity-dependent memory switching and behavior of Ag dendrite in Ag-photodoped amorphous As ₂ S ₃ films", Journal of Applied Physics, Vol. 47, No. 5, June, 1976, pps. 2767-2772.						
CAT	AT		Kawaguchi, et al., "Optical, electrical, and structural properties of amorphous Ag-Ge-S and Ag-Ge-Se films and comparison of photoinduced and thermally induced phenomena of both systems", Journal of Applied Physics, 79, June 1996, pps. 9096-9104.						
EXAMINER				DATE CONSIDERED					
Craig A. Zdon				26 APR 05					
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)		
CAT	AR	Axon Technologies Corporation, TECHNOLOGY DESCRIPTION: Programmable Metallization Cell (PMC), (pre-July 7, 2000) pp. 1-8.
CAT	AS	Shimakawa et al., Photoinduced effects and metastability in amorphous semiconductors and insulators, 44 ADVANCES IN PHYSICS No. 6, 475-568 (Taylor & Francis Ltd. 1995)
CAT	AT	Mitkova, "Insulating and Semiconducting Glasses", Editor: P. Bookchand, World Scientific, New Jersey, 2000, pps. 813-843.

EXAMINER <i>Craig A. Johnson</i>	DATE CONSIDERED <i>26 APR 05</i>
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CAT	AA	09/732,968		Githon (as Filed)	—	—	12/08/2000
CAT	AB	09/779,983		Moore	—	—	02/08/01
CAT	AC	09/943,190		Campbell, et al.	—	—	08/29/01
CAT	AD	09/943,199		Campbell, et al.	—	—	08/29/01
CAT	AE	09/943,187		Campbell, et al.	—	—	08/29/01
CAT	AF	5,238,882	08/24/03	Stalock et al.	437	52	
CAT	AG	5,380,981	11/01/94	Owen et al.	257	4	
CAT	AH	5,781,115	06/02/98	Kozicki et al.	365	182	
CAT	AI	5,896,312	04/20/99	Kozicki et al.	365	153	
CAT	AJ	5,914,893	06/22/99	Kozicki et al.	365	107	
CAT	AK	6,084,796	07/04/00	Kozicki et al.	365	153	

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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

CAT	AR		Klupe, et al., "Silver photodiffusion in amorphous Ge ₂ Se ₁₀ ", Journal of Non-Crystalline Solids 124 (1990) pps. 188-193.
CAT	AS		Kolobov, A.V., "Photodoping of amorphous chalcogenides by metals", Advances in Physics, 1991, Vol. 40, No. 5, pps. 625-684.
CAT	AT		Mitkova, et al. "Dual Chemical Role of Ag as an Additive in Chalcogenide Glasses", Physical Review Letters, Vol. 83, No. 19, pps. 3848-3851.

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					FILING DATE October 31, 2001		GROUP 2813	
U.S. PATENT DOCUMENTS								
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate		
CAT	AA	3,622,319	11/23/71	Sharp	96	27	—	
CAT	AB	3,743,847	07/03/73	Boland	250	510	—	
CAT	AC	4,269,935	05/26/81	Masters et al.	430	323	—	
CAT	AD	4,312,938	01/26/82	Drexler et al.	430	496	—	
CAT	AE	4,320,191	03/16/82	Yoshikawa et al.	430	296	—	
CAT	AF	4,795,657	01/03/89	Formigoni et al.	427	96	—	
CAT	AG	4,847,674	07/11/89	Silwa et al.	357	67	—	
CAT	AH	5,177,567	01/05/93	Klersy et al.	257	4	—	
CAT	AJ	5,219,788	06/15/93	Abernathay et al.	437	187	—	
CAT	AK	5,726,083	03/10/98	Takaishi	438	210	—	
CAT	AK	5,751,012	05/12/98	Wolstenholme et al.	257	5	—	
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AL							
	AM							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
CAT	AN		Das et al., <i>Theory of the characteristic curves of the silver chalcogenide glass inorganic photoresists</i> , 54 APPL. PHYS. LETT., No. 18, pp. 1745-1747 (May 1989).					
CAT	AO		Helbert et al., <i>Intralevel hybrid resist process with submicron capability</i> , SPIE Vol. 333 SUBMICRON LITHOGRAPHY pp. 24-29 (1982)					
CAT	AP		Hilt, DISSERTATION: <i>Materials Characterization of Silver Chalcogenide Programmable Metallization Cells</i> , Arizona State University, pp. title page-114 (UMI Company, May 1999).					
EXAMINER <i>Craig A. Sho</i>				DATE CONSIDERED <i>26 APR 05</i>				
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				FILING DATE October 31, 2001	GROUP 2813			
U.S. PATENT DOCUMENTS								
*Examiner Initial	Class	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
CAT	AA	5,789,277	08/04/98	Zahorik et al.	438	95	—	
CAT	AB	5,841,150	11/24/98	Gonzalez et al.	257	3	—	
CAT	AC	5,920,788	07/06/99	Reinberg	438	466	—	
CAT	AD	5,998,066	12/07/99	Block et al.	430	5	—	
CAT	AE	6,077,729	06/20/00	Harshfield	438	128	—	
CAT	AF	6,236,059 B1	05/22/01	Wolstenholme et al.	257	3	—	
CAT	AG	6,297,170 B1	10/02/01	Gabriel et al.	438	738	—	
CAT	AH	6,300,684 B1	10/09/01	Gonzalez et al.	257	774	—	
CAT	AI	6,316,784 B1	11/13/01	Zahorik et al.	257	3	—	
CAT	AJ	6,329,606 B1	12/11/01	Freyman et al.	174	260	—	
CAT	AK	6,348,365	02/19/02	Moore et al.	438	130	—	
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AL							
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
CAT	AN		Holmquist et al., <i>Reaction and Diffusion in Silver-Arsenic Chalcogenide Glass Systems</i> ,					
			62 J. AMER. CERAMIC SOC., Nos. 3-4, pp. 183-188 (Mar.-Apr. 1979).					
CAT	AO		Huggett et al., <i>Development of silver sensitized germanium selenide photoresist by reactive</i>					
			<i>sputter etching in SF₆</i> , 42 APPL. PHYS. LETT., No. 7, pp. 592-594 (April 1983).					
CAT	AP		Kawaguchi et al., <i>Mechanism of photosurface deposition</i> , 164-166 J. NON-CRYST. SOLIDS,					
			pp. 1231-1234 (1993).					
EXAMINER <i>Craig A. Zho</i>				DATE CONSIDERED <i>26 APR 05</i>				
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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1850		SERIAL NO. 09/09/883	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT: John T. Moor et al.			
				FILING DATE October 31, 2001		GROUP 2813	
U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
CAT	AA	6,376,284 B1	04/23/02	Gonzalez et al.	438	129	—
CAT	AB	6,391,688 B1	05/21/02	Gonzalez et al.	438	128	—
CAT	AC	6,414,376 B1	07/02/02	Thakur et al.	257	640	—
CAT	AD	6,418,049 B1	07/09/02	Kozicki et al.	365	174	—
CAT	AE	6,423,628 B1	07/23/02	Li et al.	438	622	—
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						Yes	No
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)							
CAT	AN		McHardy et al., <i>The dissolution of metals in amorphous chalcogenides and the effects of electron and ultraviolet radiation</i> , 20 J. PHYS. C: SOLID STATE PHYS., pp. 4055-4075 (1987).				
CAT	AO		Miyatani, <i>Electrical Properties of Ag₂Se</i> , 13 J. Phys. Soc. Japan, p. 317 (1958).				
CAT	AP		Mizusaki et al. <i>Kinetic Studies on the Selenization of Silver</i> , 47 BUL. CHEM. SOC. JAPAN., No. 11				
			pp. 2851-2855 (November 1974).				
EXAMINER			DATE CONSIDERED				
Cray A. Zhou			26 APR 05				
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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1850		SERIAL NO. 09/200,003	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT: John T. Moore et al.			
				FILING DATE October 31, 2001		GROUP 2813	
U.S. PATENT DOCUMENTS							
Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
CAT	AA	10/077,867		Campbell et al. (as filed)			02/20/2002
CAT	AB	10/232,757		Li, et al. (as filed)			08/29/2002
	AC						
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		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
CAT	AN		Owens et al., <i>Metal-Chalcogenide Photoresists for High Resolution Lithography and Sub-Micron Structures</i> , NANOSTRUCTURE PHYSICS AND FABRICATION, pp. 447-451 (Academic Press, 1989).				
CAT	AO		Safran et al., <i>TEM study of Ag₂Se developed by the reaction of polycrystalline silver films and selenium</i> , 317 THIN SOLID FILMS, pp. 72-76 (1998).				
CAT	AP		Shimizu et al., <i>The Photo-Erasable Memory Switching Effect of Ag Photo-Doped Chalcogenide Glasses</i> , 46 BUL. CHEM. SOC. JAPAN, No. 12, pp. 3662-3665 (December 1973).				
EXAMINER <i>Craig A. Jahn</i>				DATE CONSIDERED <i>26 APR 05</i>			
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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1850	SERIAL NO. 05009,883
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						Yes	No
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)			
CAT	AN		Somogyi et al., <i>Temperature Dependence of the Carrier Mobility in Ag₂Se Layers Grown on NaCl and SiO₂ Substrates</i> , 74 ACTA PHYSICA HUNGARICA, No. 3, pp. 243-255 (1994).
CAT	AO		Tai et al., <i>Multilevel Ge-Se film based resist systems</i> , SPIE Vol. 333 SUBMICRON LITHOGRAPHY, pp. 32-39 (March 1982).
CAT	AP		Tai et al., <i>Submicron optical lithography using an inorganic resist/polymer bilevel scheme</i> , 17 J. Vac. Sci. Technol., No. 5, pp. 1169-1176 (Sept./Oct. 1980).

EXAMINER: <i>Craig A. Z...</i>	DATE CONSIDERED: <i>26 APR 05</i>
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							Yes No
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)			
CAT	AN		West, DISSERTATION: <i>Electrically Erasable Non-Volatile Memory Via electrochemical Deposition of Multifractal Aggregates</i> , Arizona State University, pp. title page-168 (UMI Co., May 1998).
VAT	AO		West et al., <i>Equivalent Circuit Modeling of the Ag As_{0.24}S_{0.37}Ag_{0.40} Ag System Prepared by Photodissolution of Ag</i> , 145 J. Electrochem. Soc., No. 9, pp. 2971-2974 (September 1998).
CAT	AP		Yoshikawa et al., <i>A new inorganic electron resist of high contrast</i> , 31 APPL. PHYS. LETT., No. 3, pp. 161-163 (August 1977).

EXAMINER <i>Craig A. Don</i>	DATE CONSIDERED <i>26 APR 05</i>
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							Yes No
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
CAT	AN	Yoshikawa et al., <i>Dry development of Se-Ge Inorganic photoresist</i> , 36 APPL. PHYS. LETT., No. 1,	pp. 107-109 (January 1980).				
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EXAMINER		Chris A. Zho		DATE CONSIDERED			
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)			
<div style="font-size: 2em; font-family: cursive;">CT</div>	AR		Johnson et al., <i>Lateral Diffusion in Ag-Se Thin-Film Couples</i> , 40 JOURNAL OF APPLIED PHYSICS, No. 1, pp. 149-152 (January 1969).
	AS		
	AT		

EXAMINER <div style="font-family: cursive; font-size: 1.2em;">Craig a. Jho</div>	DATE CONSIDERED <div style="font-family: cursive; font-size: 1.2em;">26 APR 05</div>
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.